

AUTOMOTIVE GRADE

AUIRFZ44N

HEXFET® Power MOSFET

Features

Advanced Planar Technology

- Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching

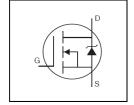
Description

- Fully Avalanche Rated
- · Repetitive Avalanche Allowed up to Tjmax

Specifically designed for Automotive applications, this Stripe Planar design of HEXFET® Power MOSFETs utilizes the latest processing techniques to achieve low on-resistance per silicon

area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of

- Lead-Free, RoHS Compliant
- Automotive Qualified *



V _{DSS}	55V
R _{DS(on)} max.	17.5mΩ
I _D	49A



G	D	S
Gate	Drain	Source

Standard Pack	
other applications.	iice

Page part number	Bookaga Typa	Standard Pack		Orderable Part Number
Base part number	Package Type	Form	Quantity	Orderable Part Nulliber
AUIRFZ44N	TO-220	Tube	50	AUIRFZ44N

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	49	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	35	Α
I _{DM}	Pulsed Drain Current ①	160	
$P_D @ T_C = 25^{\circ}C$	Power Dissipation	94	W
	Linear Derating Factor	0.63	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ©	150	1
Single Pulse Avalanche Energy Tested Value ©		530	— mJ
I _{AR} Avalanche Current ①		25	А
E _{AR}	Repetitive Avalanche Energy ①	9.4	mJ
dv/dt	Peak Diode Recovery dv/dt®	5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case		1.5	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

HEXFET® is a registered trademark of Infineon.

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.058		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance			17.5	mΩ	V _{GS} = 10V, I _D = 25A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
gfs	Forward Trans conductance	19			S	$V_{DS} = 25V, I_{D} = 25A$ @
	Drain-to-Source Leakage Current			25		$V_{DS} = 55 \text{ V}, V_{GS} = 0 \text{ V}$
I _{DSS}	Drain-to-Source Leakage Current			250	μΑ	$V_{DS} = 44V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-100	I IIA	V _{GS} = -20V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Q_g	Total Gate Charge	 	63		I _D = 25A
Q_{gs}	Gate-to-Source Charge	 	14	nC	V _{DS} = 44V
Q_{gd}	Gate-to-Drain Charge	 	23		V_{GS} = 10V , See Fig. 6 and 13
$t_{d(on)}$	Turn-On Delay Time	 12			$V_{DD} = 28V$
t _r	Rise Time	 60		no	I _D = 25A
$t_{d(off)}$	Turn-Off Delay Time	 44		ns	$R_G = 12\Omega$
t _f	Fall Time	 45			V _{GS} = 10V, See Fig. 10 ④
L_D	Internal Drain Inductance	 4.5			Between lead, 6mm (0.25in.)
L _S	Internal Source Inductance	 7.5			from package and center of die contact
C _{iss}	Input Capacitance	 1470			$V_{GS} = 0V$
Coss	Output Capacitance	 360		pF	$V_{DS} = 25V$
C_{rss}	Reverse Transfer Capacitance	88			f = 1.0MHz, See Fig. 5
E _{As}	Single pulse Avalanche Energy	 530 ^⑤	150⑥	mJ	I _{AS} = 25A, L = 0.47mH

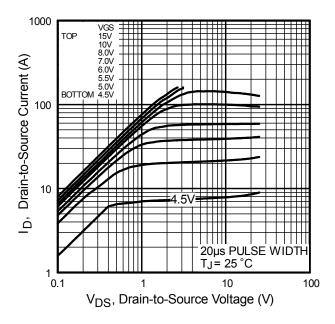
Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)			49		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			160		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	٧	$T_J = 25^{\circ}C, I_S = 25A, V_{GS} = 0V$ @
t _{rr}	Reverse Recovery Time		63	95	ns	$T_J = 25^{\circ}C$, $I_F = 25A$
Qrr	Reverse Recovery Charge		170	260	nC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25^{\circ}C$, L = 0.48mH, $R_G = 25\Omega$, $I_{AS} = 25$ A (See fig. 12)
- $\begin{array}{ll} \mbox{ } & I_{SD} \leq 25 \mbox{A, di/dt} \leq \ 230 \mbox{A/\mu s, V}_{DD} \leq \ \mbox{V}_{(BR)DSS}, \ \mbox{T}_{J} \leq 175 \mbox{°C} \\ \mbox{ } & \mbox{Pulse width} \leq 400 \mbox{\mu s; duty cycle} \leq 2\%. \\ \end{array}$
- © This is a typical value at device destruction and represents operation outside rated limits.
- © This is a calculated value limited to $T_J = 175^{\circ}C$.





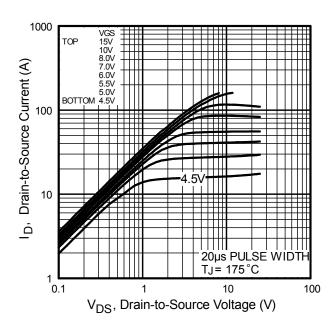
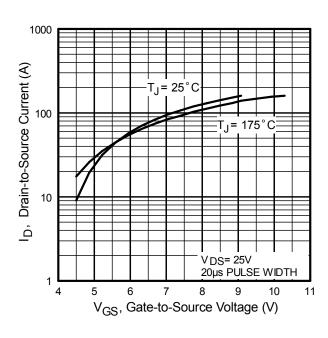


Fig. 1 Typical Output Characteristics

Fig. 2 Typical Output Characteristics





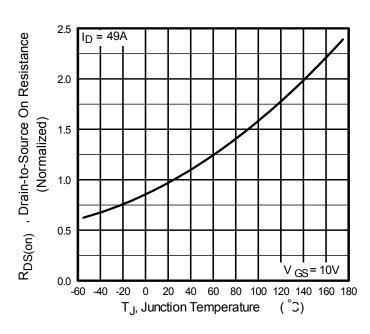


Fig. 4 Normalized On-Resistance Vs. Temperature



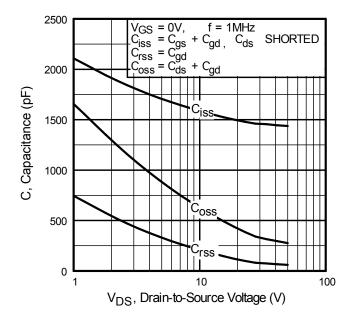


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

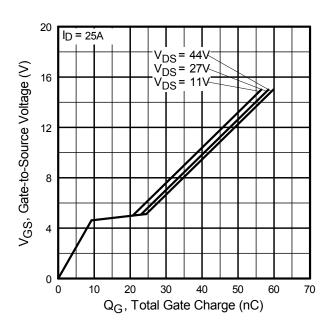


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

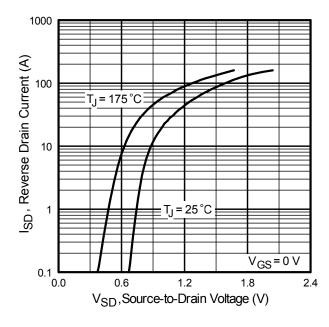


Fig. 7. Typical Source-to-Drain Diode Forward Voltage

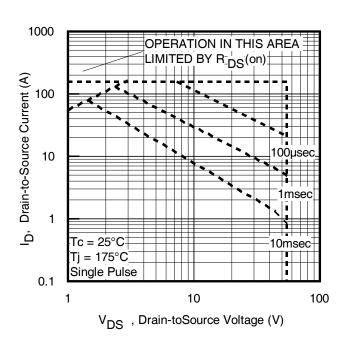


Fig 8. Maximum Safe Operating Area



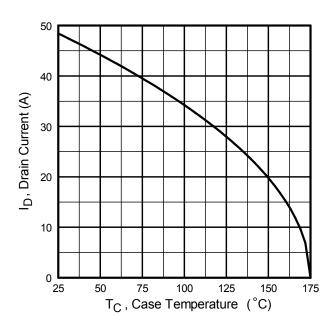


Fig 9. Maximum Drain Current vs. Case Temperature

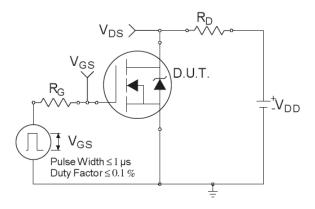


Fig 10a. Switching Time Test Circuit

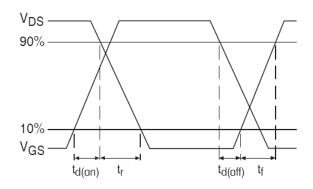


Fig 10b. Switching Time Waveforms

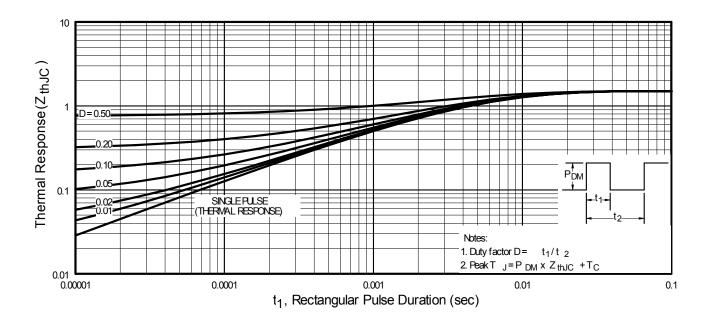


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



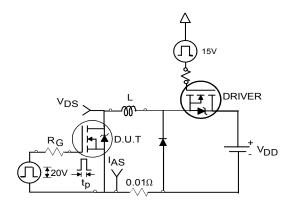


Fig 12a. Unclamped Inductive Test Circuit

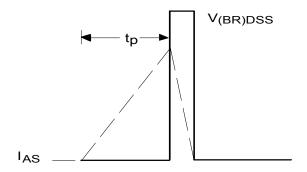


Fig 12b. Unclamped Inductive Waveforms

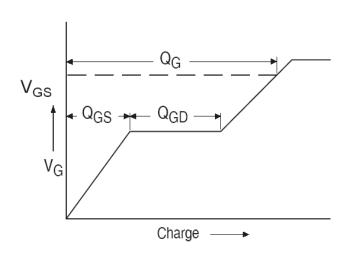


Fig 13a. Gate Charge Waveform

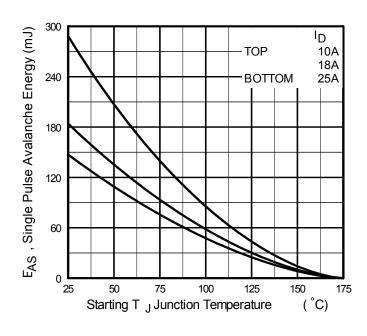


Fig 12c. Maximum Avalanche Energy vs. Drain Current

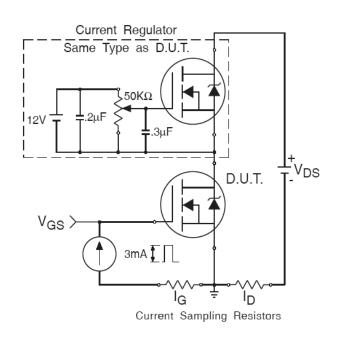
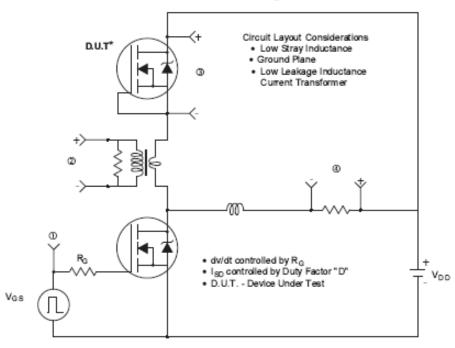


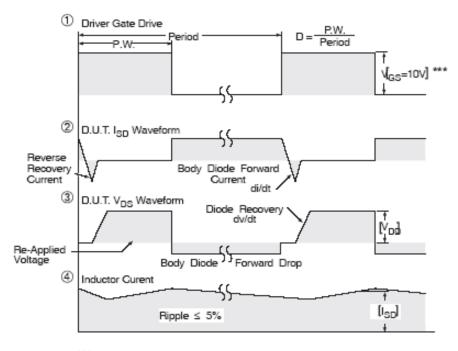
Fig 13b. Gate Charge Test Circuit



Peak Diode Recovery dv/dt Test Circuit



* Reverse Polarity of D.U.T for P-Channel

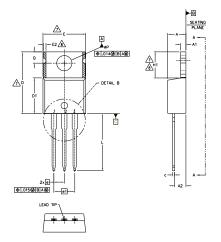


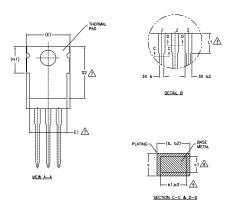
*** V_{GS} = 5.0V for Logic Level and 3V Drive Devices

Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs



TO-220AB Package Outline (Dimensions are shown in millimeters (inches))





NOTES:

- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.

- DIMENSIONING AND TOLERANGING AS PER ASME 114.5 M = 1994.

 DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].

 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.

 DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH

 SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

5. DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.

- CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIMETERS		OL MILLIMETERS		INC	HES	
	MIN.	MAX.	MIN.	MAX.	NOTES		
Α	3.56	4.83	.140	.190			
A1	1.14	1.40	.045	.055			
A2	2.03	2.92	.080	.115			
b	0.38	1.01	.015	.040			
b1	0.38	0.97	.015	.038	5		
b2	1.14	1.78	.045	.070			
b3	1,14	1.73	.045	.068	5		
c	0.36	0.61	.014	.024			
c1	0.36	0.56	.014	.022	5		
D	14.22	16.51	.560	.650	4		
D1	8.38	9.02	.330	.355			
D2	11.68	12.88	.460	.507	7		
E	9.65	10.67	.380	.420	4,7		
E1	6.86	8.89	.270	.350	7		
E2	-	0.76	_	.030	8		
e	2.54		.100	BSC			
e1	5.08	BSC	.200	BSC			
H1	5.84	6.86	.230	.270	7,8		
L	12.70	14.73	.500	.580			
L1	3.56	4.06	.140	.160	3		
ØΡ	3.54	4.08	.139	.161			
Q	2.54	3.42	.100	.135			

LEAD ASSIGNMENTS

HEXFET

- 1.- GATE 2.- DRAIN 3.- SOURCE

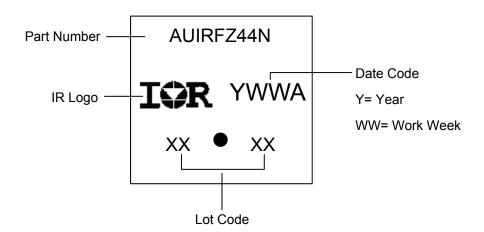
IGBTs, CoPACK

1.- GATE 2.- COLLECTOR 3.- EMITTER

DIODES

- 1.- ANODE 2.- CATHODE 3.- ANODE

TO-220AB Part Marking Information



TO-220AB package is not recommended for Surface Mount Application.



Qualification Information

		Automotive (per AEC-Q101)				
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.				
Moisture Sensitivity Level 3L-TO-220AB			N/A			
	Manalata a Manalat		Class M3 (+/- 400V) [†]			
	Machine Model	AEC-Q101-002				
ECD	Lluman Dady Madal	Class H1C (+/- 1250V) [†]				
ESD	Human Body Model	AEC-Q101-001				
	Observat Davis - Madal		Class C5 (+/- 1250V) [†]			
Charged Device Model		AEC-Q101-005				
RoHS Co	mpliant	Yes				

[†] Highest passing voltage.

Revision History

Date	Comments			
9/25/2017	 Updated datasheet with corporate template. Corrected typo error on package outline and part marking on page 8. 			

Published by Infineon Technologies AG 81726 München, Germany © Infineon Technologies AG 2015 All Rights Reserved.

IMPORTANT NOTICE

The information given in this document shall in <u>no event</u> be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie"). With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

For further information on the product, technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies office (www.infineon.com).

WARNINGS

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may <u>not</u> be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.